A METHOD FOR THE OBSERVATION OF
HELIUM II FILMS

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For the observation of helium II films and the
investigation of their behavior, a simple method
has been employed which makes use of the absorp-
tion within the film of photoelectrons ejected from
the surface upon which the film is formed. With
the aid of this method it is readily possible to fol-
low the formation of the film in various regions
of temperature and pressure. The magnitude of
the photoelectric current, characterizing the state
of the film, was measured with the aid of an inverse-
feedback electrometer amplifier connected to the
output of the apparatus described, making it pos­
sible in some cases to follow as well the kinetics
of the processes involved.

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